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INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>			Application Number	Not Yet Assigned	
			Filing Date	September 28, 2004	
			First Named Inventor	Kuniaki Okada	
			Art Unit	N/A	
			Examiner Name	Not Yet Assigned	
Sheet	1	of	1	Attorney Docket Number	62121(70904)

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
JM	AA	US-5,633,737	05/1997	Tanaka et al.	

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
JM	BA	JP-11-338379	12/1999			✓
JM	BB	JP-2001-341210	12/2001			✓
JM	BC	JP-2001-255660	09/2001			✓
JM	BD	JP-09-090336	04/1997			✓
JM	BE	JP-2000-098102	04/2000			✓

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NON PATENT LITERATURE DOCUMENTS				
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²	
JM	CA	Fujita et al., "Fabrication method of double micro lens array substrate," Japan Society of Applied Physics.		
JM	CB	Okada et al., "31a-W-11 Fabrication of double micro lens arrays using a self-alignment exposure method," Japan Society for Precision Engineering.		
JM	CC	Kitamura et al., "Fabrication Method of Double Micro Lens Array Using Self-Alignment Technology," 9th Microoptics Conference (MOC '03) Tokyo, October 29-31, 2003, pp. 114-17.		
JM	CD	Kitamura et al., "Fabrication Method of Double-Microlens Array Using Self-Alignment Technology," Japanese Journal of Applied Physics, Vol. 43, No. 8B, 2004.		

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Examiner Signature	/John McPherson/	Date Considered	01/19/2007
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